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- Inputs Are TTL-Voltage Compatible
- *EPIC* [™] (Enhanced-Performance Implanted CMOS) 1-μm Process
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPS

description

The 'ACT08 are quadruple 2-input positive-AND gates. These devices perform the Boolean functions $Y = A \bullet B$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The SN54ACT08 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74ACT08 is characterized for operation from -40° C to 85°C.



	(04011 9410)										
INP	JTS	OUTPUT									
Α	В	Y									
Н	Н	Н									
L	Х	L									
х	L	L									

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, DB, J, N, PW, and W packages.



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SN54ACT08 J OR W PACKAGE						
SN74ACT08 D, DB, N, OR PW PACKAGE						
(TOP VIEW)						

1A [1	\cup	14	þ	V _{CC} 4B
1B [2		13	þ	4B
1Y [3		12	þ	4A
2A [4		11	þ	4Y
2B [5		10	þ	3B
2Y [6		9	þ	ЗA
GND [7		8	þ	3Y

SN54ACT08 ... FK PACKAGE (TOP VIEW)



NC - No internal connection

logic diagram, each gate (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} Input voltage range, V_I (see Note 1) Output voltage range, V_O (see Note 1) Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) Continuous output current, I_O ($V_O = 0$ to V_{CC}) Continuous current through V_{CC} or GND Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2	$\begin{array}{ccc} -0.5 \mbox{ V to } V_{CC} + 0.5 \mbox{ V} \\ -0.5 \mbox{ V to } V_{CC} + 0.5 \mbox{ V} \\ \pm 20 \mbox{ mA} \\ \pm 20 \mbox{ mA} \\ \pm 50 \mbox{ mA} \\ \pm 200 \mbox{ mA} \end{array}$
Storage temperature range, T _{stg}	

⁺ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

recommended operating conditions (see Note 3)

		SN54ACT08 MIN MAX				UNIT
VCC	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
VIL	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	VCC	0	VCC	V
VO	Output voltage	0	VCC	0	VCC	V
ЮН	High-level output current		-24		-24	mA
IOL	Low-level output current		24		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	8	0	8	ns/V
Т _А	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



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PARAMETER	TEST CONDITIONS	Vee	$T_A = 25^{\circ}C$		SN54	ACT08	SN74A	CT08	UNIT	
FARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	I _{OH} = - 50 μA	4.5 V	4.4	4.49		4.4		4.4		
	$OH = -30 \mu A$	5.5 V	5.4	5.49		5.4		5.4		
Vou	I _{OH} = – 24 mA	4.5 V	3.86			3.7		3.76		V
VOH	IOH = -24 IIIA	5.5 V	4.86			4.7		4.76		V
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
	I _{OL} = 50 μA	4.5 V		0.001	0.1		0.1		0.1	· · · · · · · · · · · · · · · · · · ·
		5.5 V		0.001	0.1		0.1		0.1	
Mai	I _{OL} = 24 mA	4.5 V			0.36		0.5		0.44	
VOL	OL = 24 MA	5.5 V			0.36		0.5		0.44	
	I _{OL} = 50 mA [†]	5.5 V					1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65	
lj	$V_{I} = V_{CC} \text{ or } GND$	5.5 V			± 0.1		±1		±1	μΑ
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			2		80		20	μA
ΔI_{CC}^{\ddagger}	One input at 3.4 V, Other inputs at GND or V_{CC}	5.5 V		0.6			1.6		1.5	mA
Ci	$VI = V_{CC}$ or GND	5 V		4.5						pF

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V $\pm\,$ 0.5 V (unless otherwise noted) (see Figure 1)

ſ	PARAMETER	FROM	то	T _A = 25°C SN54ACT08		СТ08	SN74ACT08		UNIT		
	FARAINETER	(INPUT) (OUTPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	^t PLH	A or P	V	1	6.5	9	1	10	1	10	
	^t PHL	A or B	T	1	6.5	9	1	10	1	10	ns

operating characteristics, V_{CC} = 5 V, T_A = 25° C

PARAMETER		TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance	C _L = 50 pF, f = 1 MHz	20	pF



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_r \leq 2.5 ns, t_f \leq 2.5 ns. C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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